Notice of References Cited Application/Control No. 10/658,664 Examiner FAWAAD HAIDER Applicant(s)/Patent Under Reexamination WEI, HUNG-SHAN Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,920,846	07-1999	Storch et al.	705/7
*	В	US-6,088,626	07-2000	Lilly et al.	700/100
*	С	US-6,092,189	07-2000	Fisher et al.	713/1
*	D	US-6,151,582	11-2000	Huang et al.	705/8
*	Е	US-2002/0082893	06-2002	Barts et al.	705/8
*	F	US-2003/0149608	08-2003	Kall et al.	705/8
*	G	US-7,124,101	10-2006	Mikurak, Michael G.	705/35
*	Н	US-7,324,966	01-2008	Scheer, Robert H.	705/28
*	I	US-2003/0177050	09-2003	Crampton et al.	705/8
*	J	US-2002/0188499	12-2002	Jenkins et al.	705/10
*	К	US-2002/0147622	10-2002	Drolet et al.	705/7
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.